## Issue Classification



Application/Control No.	Applicant(s)/Patent Under Reexamination
10574468	MIURA ET AL.
Examiner	Art Unit
Examino	7111 01111
DEREK S CHAPEL	2872
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ORIGINAL							INTERNATIONAL CLASSIFICATION									
CLASS SUBCLASS					CLAIMED							NON-CLAIMED				
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CROSS REFERENCE(S)																
CLASS	SUI	BCLASS (ONE	ONE SUBCLASS PER BLOCK)													
359	900															

	Claims renumbered in the same order as presented by applicant							☐ CPA ☐ T.D. ☐ R.1.4					47		
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
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/DEREK S CHAPEL/ Examiner.Art Unit 2872	3/10/2009	Total Claims Allowed:			
(Assistant Examiner)	(Date)				
/STEPHONE B ALLEN/ Supervisory Patent Examiner.Art Unit 2872	03/12/2009	O.G. Print Claim(s)	O.G. Print Figure		
(Primary Examiner)	(Date)	1	2		

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